

PATENT ABSTRACTS OF JAPAN

(11)Publication number : 2005-038216

(43)Date of publication of application : 10.02.2005

(51)Int.Cl.

G06N 3/00
H01L 29/00
// G06F 17/50

(21)Application number : 2003-275037

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(22)Date of filing : 16.07.2003

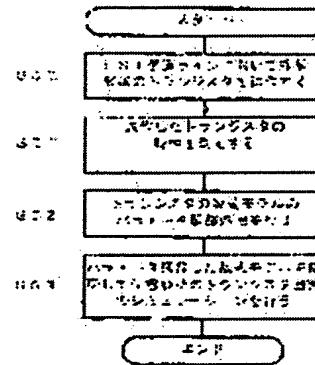
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(54) PARAMETER ADJUSTING DEVICE

(57)Abstract:

PROBLEM TO BE SOLVED: To perform an efficient and precise parameter adjustment by applying a genetic algorithm to the parameter adjustment for a physical model of a transistor.

SOLUTION: A parameter adjusting device is provided with a means for generating a new parameter gene by special crossover processing, a normalization means for applying to a parameter being a real number, and an evaluation means for evaluating the parameter so that it will match a characteristic unique to the transistor (MOSFET) highly precisely. In the above configuration, it becomes possible to apply the genetic algorithm to the parameter adjustment for the physical model of the transistor, so that an optimum parameter group can be determined in a short time and a precise circuit simulation can be performed using the parameter.



LEGAL STATUS

[Date of request for examination] 05.06.2006

[Date of sending the examiner's decision of rejection]

[Kind of final disposal of application other than the examiner's decision of rejection or application converted registration]

[Date of final disposal for application]

[Patent number]

[Date of registration]

[Number of appeal against examiner's decision of rejection]

[Date of requesting appeal against examiner's decision of rejection]

[Date of extinction of right]